

XF-U 2.5-1

H-Field Probe 30 MHz up to 6 GHz



Short description

The XF-U 2.5-2 near-field probe is designed for the selective measurements of RF currents in conducting paths, component connectors, SMD components, and IC pins. The probe head has a magnetically active gap with an approx. width of 0.5 mm. To use, the head should be positioned directly onto the measured object.

The XF-U 2.5-2 is a passive near-field probe that is designed for SMD components (pins). The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

| | |
|-----------------------|----------------------------|
| Frequency range | 30 MHz ... 6 GHz |
| Resolution | ≈ 0.5 mm |
| Probe head dimensions | $\varnothing \approx 4$ mm |
| Connector - output | SMA, female, jack |
| Weight | 15 g |

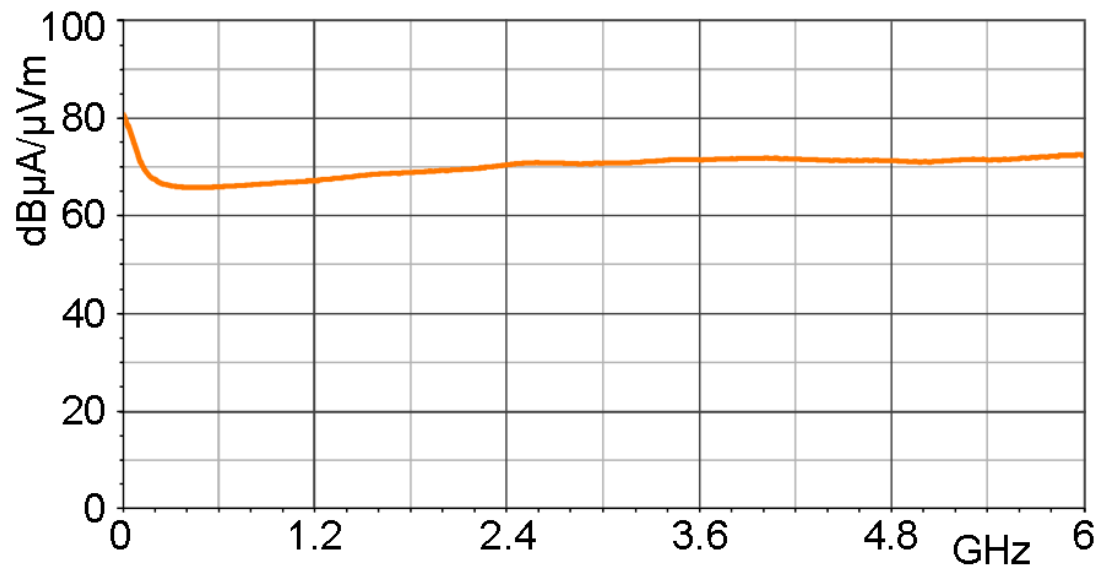
XF-U 2.5-1

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Frequency response [dB μ V] / [dB μ A/m]



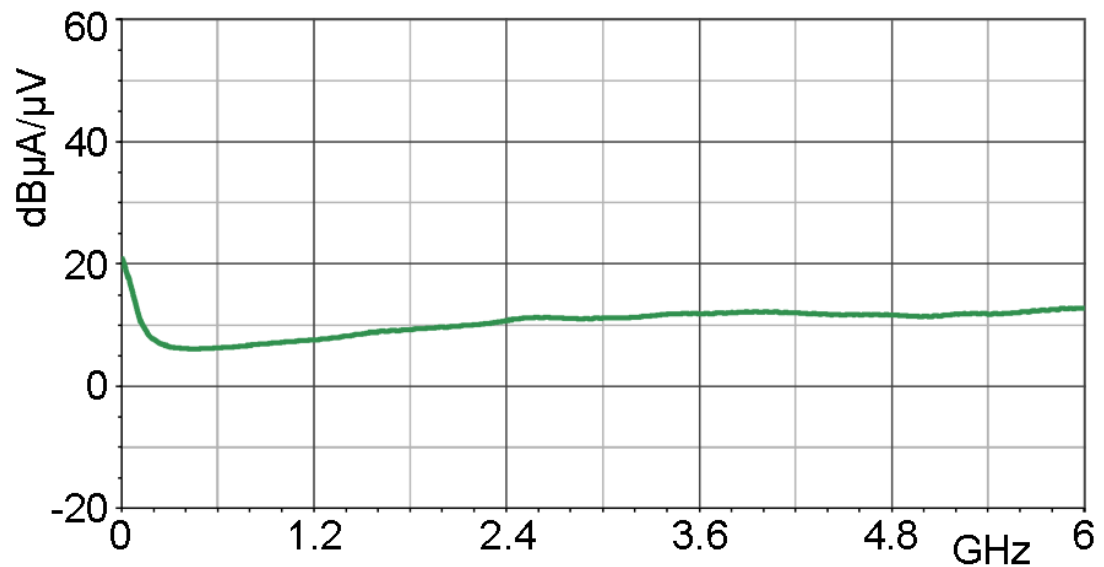
H-field correction curve [dB μ A/m] / [dB μ V]



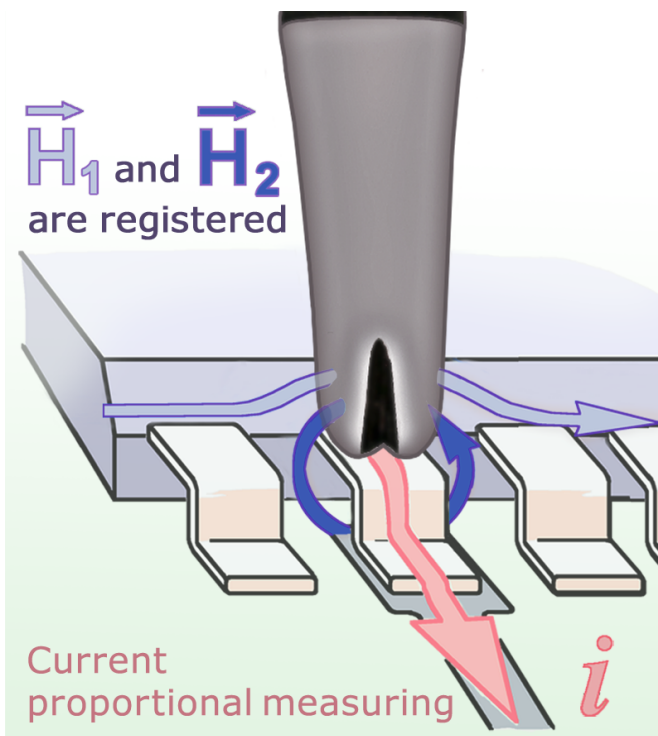
XF-U 2.5-1

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Current correction curve [dB μ A] / [dB μ V]



Measuring principles



XF-U 2.5-1

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Probe head

